

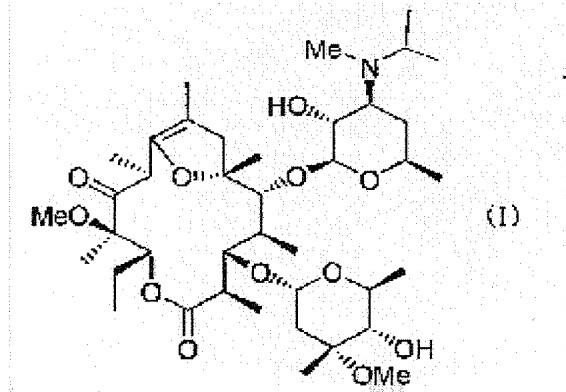
Amendments to the Claims

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

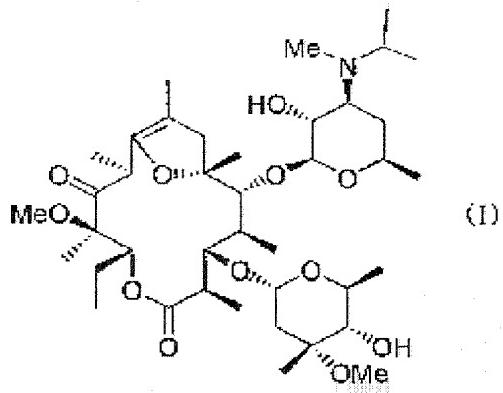
Claims 1-7. (Cancelled)

8. (Original) A hemifumarate crystal of a compound of formula (I):



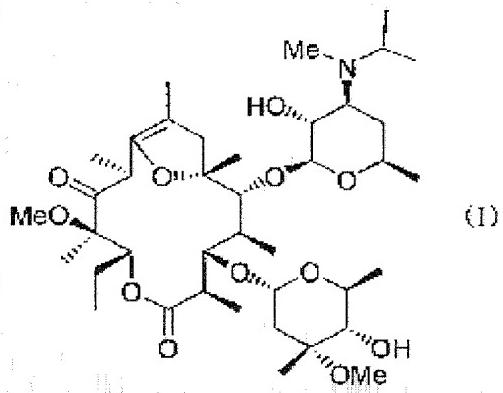
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4° , 10.4° , 10.7° and 12.1° .

9. (Original) A hemifumarate crystal of a compound of formula (I):



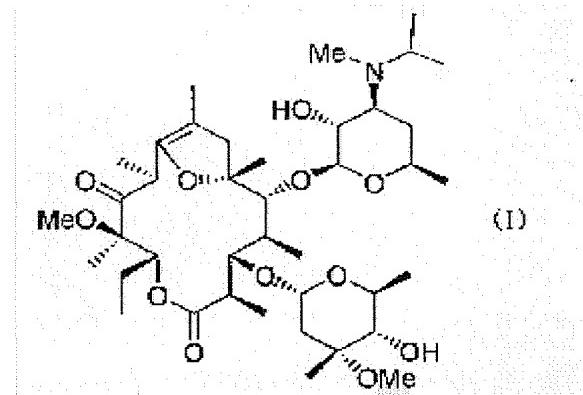
containing acetone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

10. (Previously Presented) A hemifumarate crystal of a compound of formula (I) :



containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

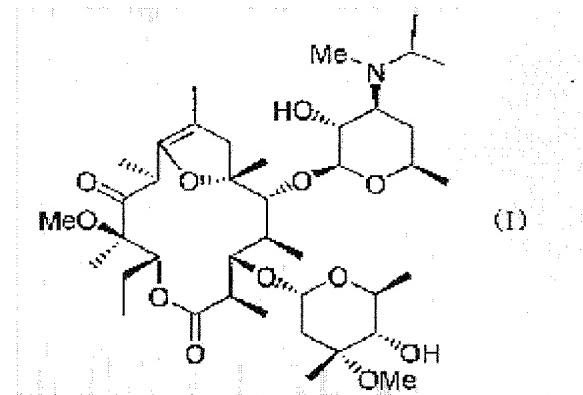
11. (Original) A hemifumarate crystal of a compound of formula (I) :



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

Claims 12-15. (Cancelled)

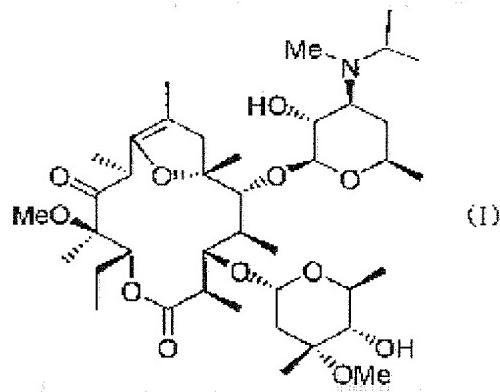
16. (Previously Presented) A process for preparing a hemifumarate anhydrate of a compound of formula (I) :



characterized by 2-theta angle positions in the powder X-ray

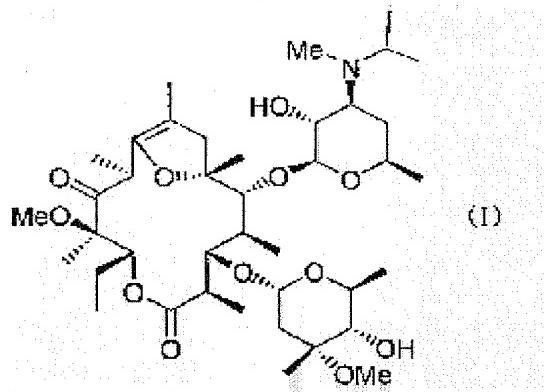
diffraction pattern of 7.1° , 13.5° and 14.2° , said process comprising the step of obtaining said anhydrate by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. (Previously Presented) A process for preparing a hemifumarate hydrate of a compound of formula (I):



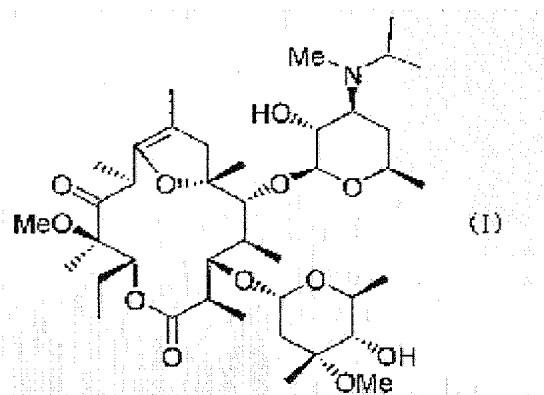
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles $2\theta = 7.1^\circ$ and 14.2° , said process comprising the step of obtaining said hydrate by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. (Previously Presented) A process for preparing a hemifumarate hydrate of a compound of formula (I):



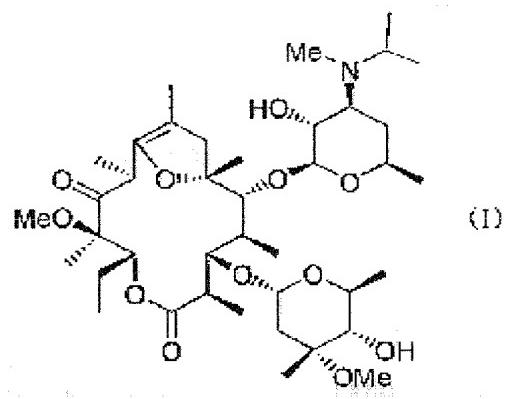
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising the step of conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , wherein said anhydrate is obtained by drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

19. (New) A process for preparing a hemifumarate crystal of a compound of formula (I) :



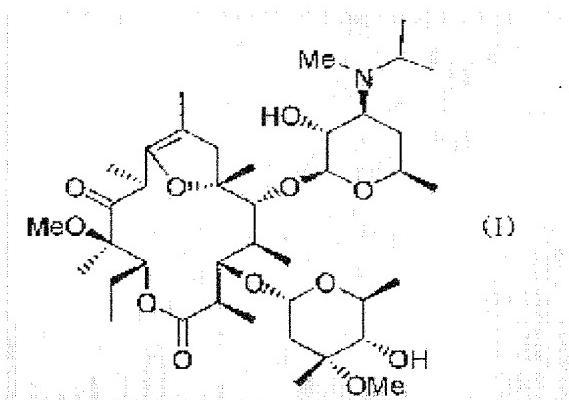
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5° , said process comprising eth step of stirring crystal form E in a mixed solvent of ethyl acetate and water, to obtain said hemifumarate crystal.

20. (New) a hemifumarate crystal of a compound of formula (I):



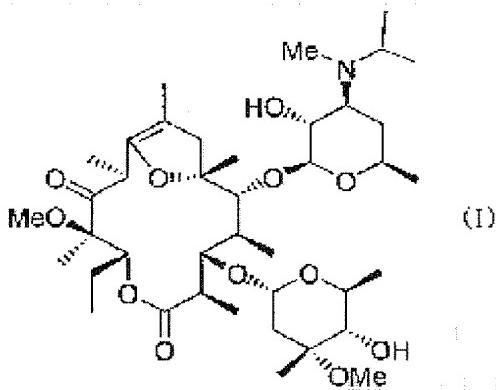
Characterized by 2-theta bangle positions in the powder X-ray diffraction pattern of 6.6° and 8.5° , which crystal is obtained by the process of claim 19.

21. (New) A process for preparing a hemifumarate crystal of a compound of formula (I):



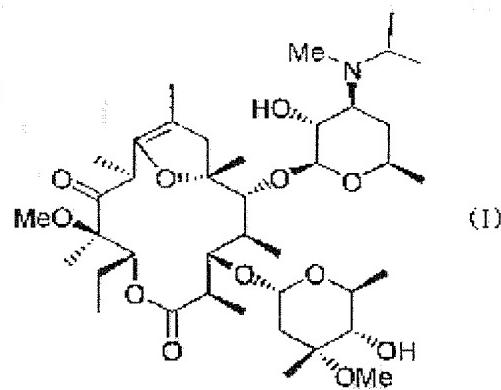
Characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, said process comprising the steps of treating crystal form C at 20-40°C in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, and stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain said hemifumarate crystal.

22. (New) A hemifumarate crystal of a compound of formula (I) :

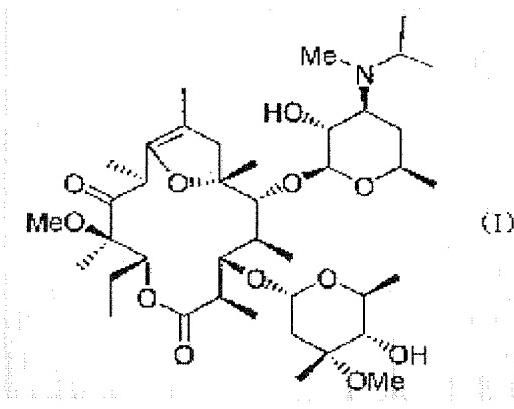


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, which crystal is obtained by the process of claim 21.

23. (New) A process for preparing a hemifumarate anhydrate of a compound of formula (I) :

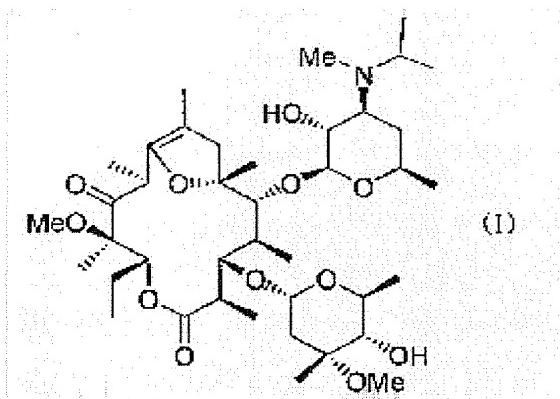


characterized by 2-theta positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , said process comprising stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I) :



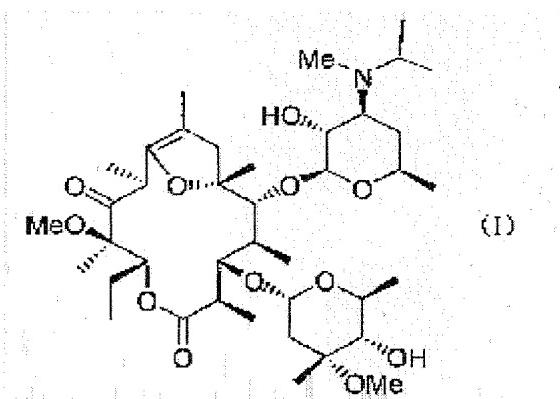
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5° , and drying the hemifumarate crystal under reduced pressure to obtain said anhydride.

24. (New) A hemifumarate anhydride of a compound of formula (I):



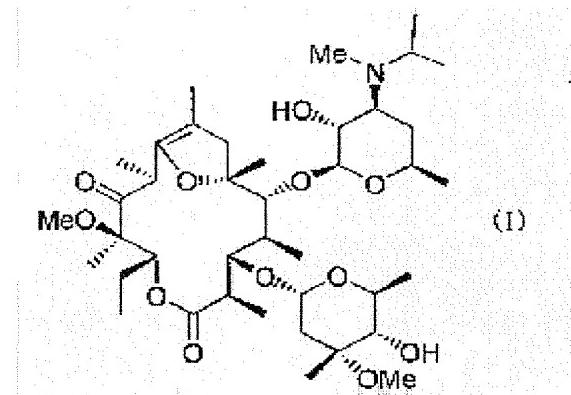
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , which is obtained by the process of claim 23.

25. (New) A process for preparing a hemifumarate anhydride of a compound of formula (I):



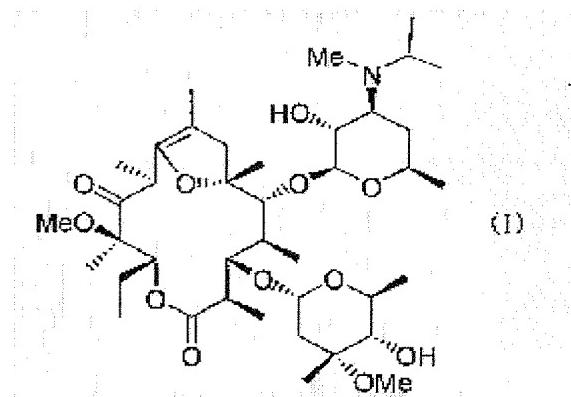
characterized by 2-theta angle positions in the powder X-ray diffraction pattern fog 7.1° , 13.5° and 14.2° , said process comprising treating Crystal form C at $20\text{--}40^\circ\text{C}$ in a mixed solvent of ethyl acetate and water to obtain Crystal Form E,

and stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I) :



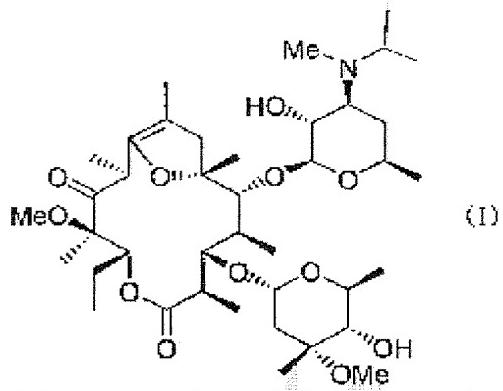
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, and drying the hemifumarate crystal under reduced pressure to obtain said anhydrate.

26. (New) A hemifumarate anhydride of a compound of formula (I) :

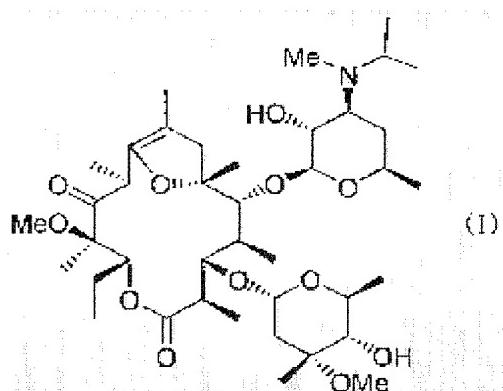


Characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.15° and 14.2° , which crystal is obtained by the process of claim 25.

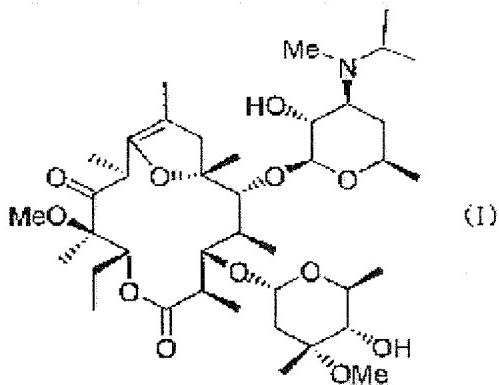
27. (New) A process for preparing a hemifumarate hydrate of a compound of formula (I) :



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I) :

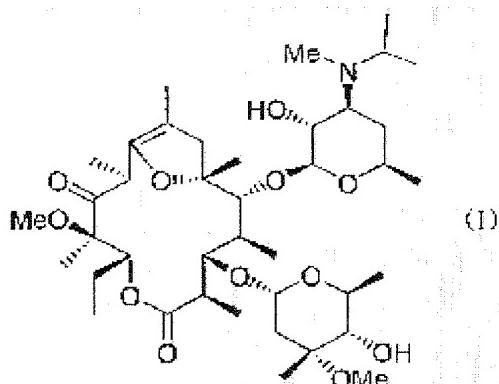


Characterized by 2-theta angle positions in the powder X-ray diffraction patterns of 6.6° and 8.5° , and drying the hemifumarate crystal under reduced pressure to obtain a hemifumarate anhydrate of a compound of formula (I) :



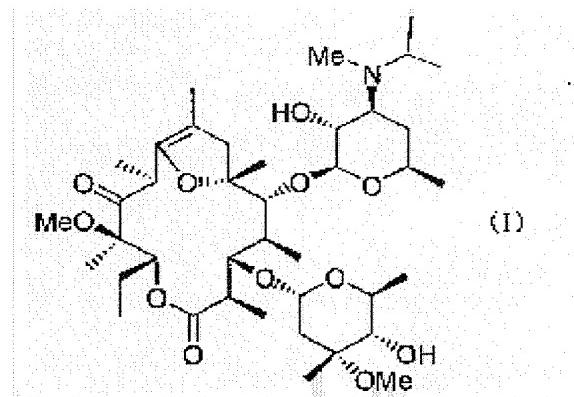
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , and conditioning the anhydrate to obtain said hydrate.

28. (New) A hemifumarate hydrate of a compound of formula (I) :

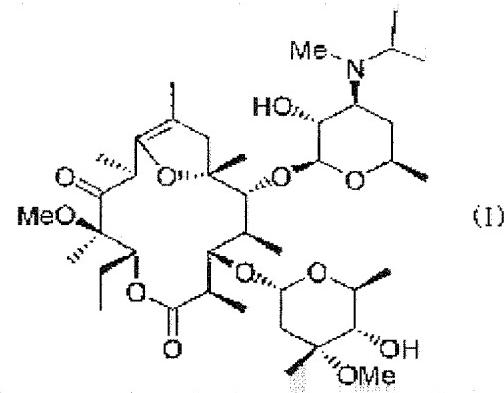


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , which crystal is obtained by the process of claim 27.

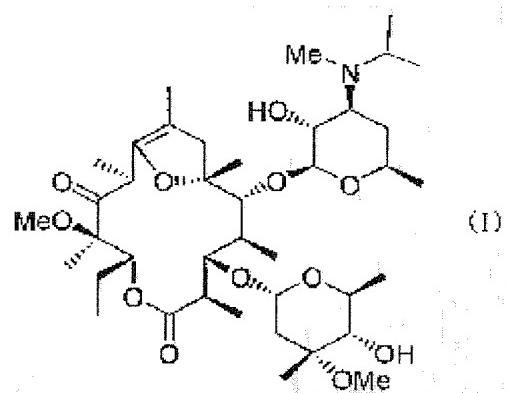
29. (New) A process for preparing a hemifumarate hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising treating Crystal Form C at $20\text{--}40^\circ\text{C}$ in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, and stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I):

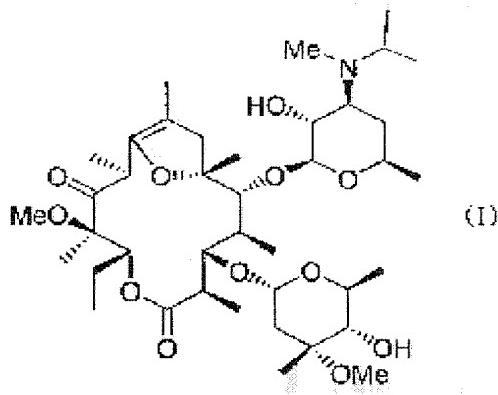


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5° , and drying the hemifumarate crystal under reduced pressure to obtain a hemifumarate of a compound of formula (I) :



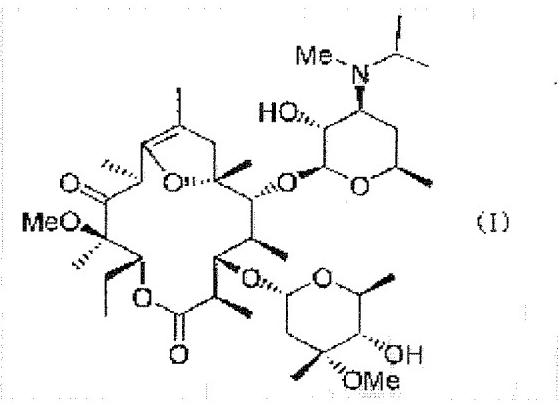
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , and conditioning the anhydrate to obtain said hydrate.

30. (New) A hemifumarate hydrate of a compound of formula (I) :

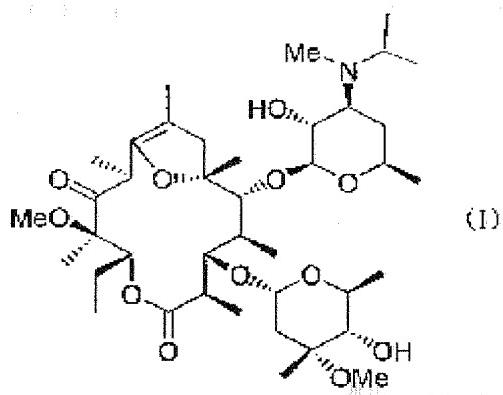


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, which is obtained by the processes of claim 29.

31. (New) a process for preparing a hemifumarate hydrate of a compound of formula (I) :

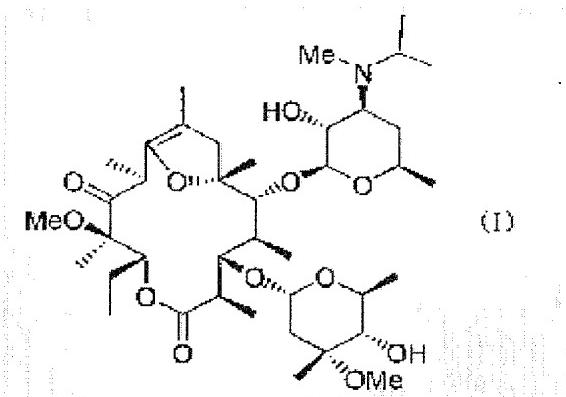


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising stirring Crystal Form E in a mixed solvent of ethyl acetate and water to obtain a hemifumarate crystal of a compound of formula (I) :



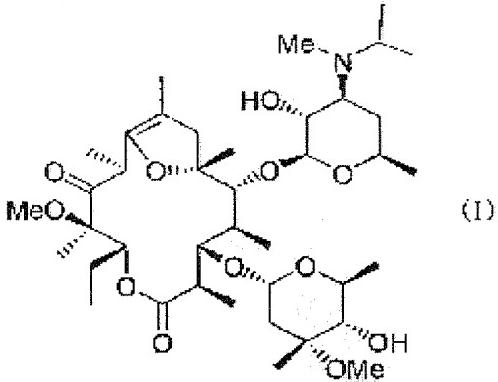
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, and drying the hemifumarate crystal under reduced pressure.

32. (New) A hemifumarate hydrate of a compound of formula (I) :

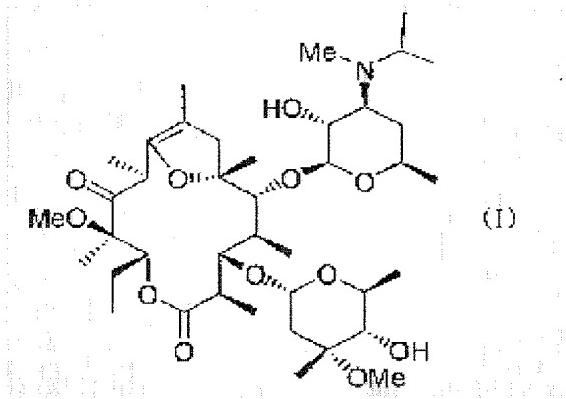


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, which is obtained by the process of claim 31.

33. (New) A process for preparing a hemifumarate hydrate of a compound of formula (I) :

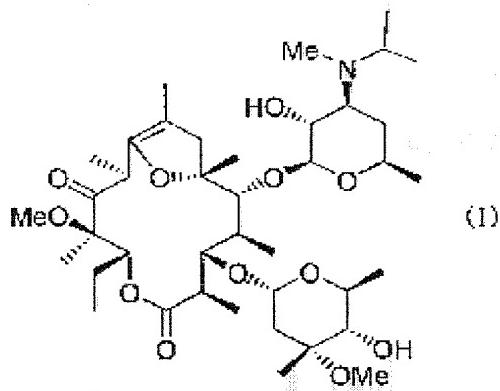


characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , said process comprising treating Crystal form C at $20\text{--}40^\circ\text{C}$ in a mixed solvent of ethyl acetate and water to obtain Crystal Form E, and stirring the Crystal Form E in a mixed solvent of ethyl acetate and water at less than 20°C to obtain a hemifumarate crystal of a compound of formula (I) :



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5° , and drying the hemifumarate crystal under reduced pressure.

34. (New) A hemifumarate hydrate of a compound of formula (I) :



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° , which is obtained by the process of claim 33.